

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No.09/559,903
Filing DateApril 26, 2000
Inventor Zhiping Yin et al.
Assignee Micron Technology, Inc.
Group Art Unit..... 2815
Examiner Eckert II, G.
Attorney's Docket No.MI22-1427
Title: Circuitry and Gate Stacks

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

From: Jennifer J. Taylor, Ph.D. (Tel. 509-624-4276; Fax 509-838-3424)
Wells St. John P.S.
601 W. First Avenue, Suite 1300
Spokane, WA 99201-3828

Dear Sir:

The Examiner's attention is directed to the references which are listed on the attached Form PTO-1449 and copies of which are attached.

Citation of these references is respectfully requested.

A check in the amount of \$180.00 is enclosed to cover the fee specified under 37 C.F.R. § 1.17(p).

Respectfully submitted,

Dated:

August 31, 2004

By:

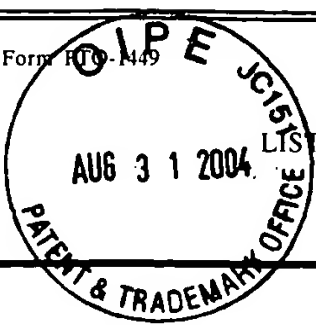
Jennifer J. Taylor
Jennifer J. Taylor, Ph.D.
Reg. No. 48,711

09/03/2004 BABRAHA1 00000017 09559903

01 FC:1806

180.00 OP

EV372459695

Form PTO-1449 		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1427		SERIAL NO. 09/559,903	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yin et al.			
				FILING DATE April 26, 2000		GROUP 2815	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,638,875	10-2003	Han et al.			
	AB	6,720,247	04-2004	Kirkpatrick et al.			
	AC	6,723,631	04-2004	Noguchi et al.			
	AD	6,627,535	09-2003	MacNeil et al.			
	AE	5,593,741	01-1997	Ikeda			
	AF	2003/0077916	04-2003	Xu et al.			
	AG	2003/0207594	11-2003	Catabay et al.			
	AH	2004/0071878	04-2004	Schuhmacher et al.			
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	A R						
	AS						
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							